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CONFIRMATION NO. 3834

<b>SERIAL NUMBER</b> 10/659,060	<b>FILING OR 371(c) DATE</b> 09/09/2003 <b>RULE</b>	<b>CLASS</b> 356	<b>GROUP ART UNIT</b> 2877	<b>ATTORNEY DOCKET NO.</b> 09712-332001 / Z-433
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## APPLICANTS

Peter J. De Groot, Middletown, CT; *mgd*

## \*\* CONTINUING DATA \*\*\*\*\*

This appln claims benefit of 60/409,147 09/09/2002 and claims benefit of 60/452,615 03/06/2003  
and claims benefit of 60/478,300 06/13/2003 *mgd*

## \*\* FOREIGN APPLICATIONS \*\*\*\*\*

*NONE mgd*

## IF REQUIRED, FOREIGN FILING LICENSE GRANTED \*\*

12/01/2003

Foreign Priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no	STATE OR COUNTRY CT	SHEETS DRAWING 7	TOTAL CLAIMS <i>46 53</i>	INDEPENDENT CLAIMS <i>86 mgd</i>
35 USC 119 (a-d) conditions met <input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> Met after Allowance				
Verified and Acknowledged Examiner's Signature <i>mgd</i> Initials <i>mgd</i>				

## ADDRESS

26161

## TITLE

Interferometry method for ellipsometry, reflectometry, and scatterometry measurements, including characterization of thin film structures

<b>FILING FEE RECEIVED</b> 2232	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:	<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees ( Filing ) <input type="checkbox"/> 1.17 Fees ( Processing Ext. of time ) <input type="checkbox"/> 1.18 Fees ( Issue ) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit
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